

### **PCTEST**

7185 Oakland Mills Road, Columbia, MD 21046 USA Tel. 410.290.6652 / Fax 410.290.6654 http://www.pctest.com



## **PART 27 MEASUREMENT REPORT**

**Applicant Name:** 

Samsung Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea **Date of Testing:** 

06/10/2021 - 07/23/2021

Test Site/Location:

PCTEST Lab. Columbia, MD, USA

**Test Report Serial No.:** 1M2106100066-04.A3L

FCC ID: A3LSMF711JPN

APPLICANT: Samsung Electronics Co., Ltd.

Application Type:CertificationModel:SC-54BAdditional Model(s):SCG12

**EUT Type:** Portable Handset

FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)

FCC Rule Part: 27

**Test Procedure(s):** ANSI C63.26-2015, ANSI/TIA-603-E-2016, KDB 971168 D01 v03r01,

KDB 648474 D03 v01r04

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President





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				EF	RP	EII	RP	
Mode	Bandwidth	Modulation	Tx Frequency Range [MHz]	Max. Power [W]	Max. Power [dBm]	Max. Power [W]	Max. Power [dBm]	Emission Designator
	10 MHz	QPSK	704.0 - 711.0	0.041	16.13	0.067	18.28	8M96G7D
	IU WITZ	16QAM	704.0 - 711.0	0.037	15.67	0.061	17.82	8M95W7D
	5 MHz	QPSK	701.5 - 713.5	0.043	16.30	0.070	18.45	4M50G7D
LTE Band 12	5 IVITZ	16QAM	701.5 - 713.5	0.036	15.61	0.060	17.76	4M50W7D
LIE Dand 12	3 MHz	QPSK	700.5 - 714.5	0.041	16.14	0.067	18.29	2M70G7D
		16QAM	700.5 - 714.5	0.036	15.59	0.059	17.74	2M70W7D
	4.4.541.1-	QPSK	699.7 - 715.3	0.041	16.17	0.068	18.32	1M09G7D
	1.4 MHz	16QAM	699.7 - 715.3	0.038	15.77	0.062	17.92	1M09W7D
	40 MH	QPSK	782.0	0.049	16.86	0.080	19.01	8M98G7D
1 TE D 1 40	10 MHz	16QAM	782.0	0.042	16.27	0.070	18.42	8M96W7D
LTE Band 13	E MU-	QPSK	779.5 - 784.5	0.051	17.04	0.083	19.19	4M50G7D
	5 MHz	16QAM	779.5 - 784.5	0.047	16.73	0.077	18.88	4M49W7D

## **EUT Overview (<1GHz)**

				EI		
Mode	Bandwidth	Modulation	Tx Frequency Range [MHz]	Max. Power [W]	Max. Power [dBm]	Emission Designator
	20 MHz	QPSK	1720.0 - 1745.0	0.186	22.70	18M0G7D
	20 1011 12	16QAM	1720.0 - 1745.0	0.151	21.80	18M0W7D
	15 MHz	QPSK	1717.5 - 1747.5	0.191	22.81	13M5G7D
	15 IVITZ	16QAM	1717.5 - 1747.5	0.160	22.04	13M5W7D
	10 MHz	QPSK	1715.0 - 1750.0	0.195	22.91	9M04G7D
LTE Band 4		16QAM	1715.0 - 1750.0	0.169	22.28	9M04W7D
LTE Ballu 4	5 NALI-	QPSK	1712.5 - 1752.5	0.199	22.99	4M51G7D
	5 MHz	16QAM	1712.5 - 1752.5	0.159	22.02	4M51W7D
	3 MHz	QPSK	1711.5 - 1753.5	0.193	22.86	2M70G7D
	3 IVITZ	16QAM	1711.5 - 1753.5	0.161	22.08	2M70W7D
	1 4 MU=	QPSK	1710.7 - 1754.3	0.190	22.80	1M09G7D
	1.4 MHz	16QAM	1710.7 - 1754.3	0.158	21.98	1M10W7D

EUT Overview (>1GHz)

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### 1.0 INTRODUCTION

## 1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Innovation, Science and Economic Development Canada.

### 1.2 PCTEST Test Location

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The measurement facility is compliant with the test site requirements specified in ANSI C63.4-2014.

### 1.3 Test Facility / Accreditations

assembly of contents thereof, please contact INFO@PCTEST.COM.

Measurements were performed at PCTEST Engineering Lab located in Columbia, MD 21046, U.S.A.

- PCTEST is an ISO 17025-2017 accredited test facility under the American Association for Laboratory Accreditation (A2LA) with Certificate number 2041.01 for Specific Absorption Rate (SAR), Hearing Aid Compatibility (HAC) testing, where applicable, and Electromagnetic Compatibility (EMC) testing for FCC and Innovation, Science, and Economic Development Canada rules.
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC 17065-2012 by A2LA (Certificate number 2041.03) in all scopes of FCC Rules and ISED Standards (RSS).
- PCTEST facility is a registered (2451B) test laboratory with the site description on file with ISED.

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### 2.0 PRODUCT INFORMATION

### 2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSMF711JPN**. The test data contained in this report pertains only to the emissions due to the EUT's licensed transmitters that operate under the provisions of Part 27.

The Equipment Under Test (EUT) can operate in one of three physical configurations – "Open", "Half open" and "Closed". All emissions are investigated in three modes for compliance, and the worst case radiated emissions data is shown in this report.

Test Device Serial No.: 0711M, 0035M, 0405M, 0080M

### 2.2 Device Capabilities

This device contains the following capabilities:

850/1900 GSM/GPRS/EDGE, 850 WCDMA/HSPA, Multi-band LTE, 802.11b/g/n/ax WLAN, 802.11a/n/ac/ax UNII (5GHz), Bluetooth (1x, EDR, LE), NFC, Wireless Power Transfer

### 2.3 Test Configuration

The EUT was tested per the guidance of ANSI/TIA-603-E-2016 and KDB 971168 D01 v03r01. See Section 7.0 of this test report for a description of the radiated and antenna port conducted emissions tests.

This device supports wireless charging capability and, thus, is subject to the test requirements of KDB 648474 D03 v01r04. Additional radiated spurious emission measurements were performed with the EUT lying flat on an authorized wireless charging pad (WCP) Model: EP-N5100 while operating under normal conditions in a simulated call or data transmission configuration. The worst case radiated emissions data is shown in this report.

### 2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

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### 3.0 DESCRIPTION OF TESTS

### 3.1 Evaluation Procedure

The measurement procedures described in the document titled "Land Mobile FM or PM – Communications Equipment – Measurements and Performance Standards" (ANSI/TIA-603-E-2016) and "Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems" (KDB 971168 D01 v03r01) were used in the measurement of the EUT.

### 3.2 Radiated Power and Radiated Spurious Emissions

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Figure 5.7 of Clause 5 in ANSI C63.4-2014. Absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections for measurements above 1GHz. For measurements below 1GHz, the absorbers are removed. A raised turntable is used for radiated measurement. The turn table is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. An 80cm tall test table made of Styrodur is placed on top of the turn table. A Styrodur pedestal is placed on top of the test table to bring the total table height to 1.5m.

The equipment under test was transmitting while connected to its integral antenna and is placed on a wooden turntable 80cm above the ground plane and 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer. Radiated power levels are also investigated with the receive antenna horizontally and vertically polarized. The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration band set to the emissions' occupied bandwidth, a RMS detector, RBW = 100kHz, VBW = 300kHz, and a 1 second sweep time over a minimum of 10 sweeps, per the guidelines of KDB 971168 D01 v03r01.

Per the guidance of ANSI/TIA-603-E-2016, a half-wave dipole is then substituted in place of the EUT. For emissions above 1GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator with the level of the signal generator being adjusted to obtain the same receive spectrum analyzer level previously recorded from the spurious emission from the EUT. The power of the emission is calculated using the following formula:

$$P_{d [dBm]} = P_{g [dBm]} - cable loss [dB] + antenna gain [dBd/dBi]$$

Where,  $P_d$  is the dipole equivalent power,  $P_g$  is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to  $P_{q [dBm]}$  – cable loss [dB].

For fundamental radiated power measurements, the guidance of KDB 971168 D01 v03r01 is used to record the EUT power level that is subsequently matched via the aforementioned substitution method given in ANSI/TIA-603-E-2016.

All radiated measurements are performed in a chamber that meets the site requirements per ANSI C63.4-2014. Additionally, radiated emissions below 30MHz are also validated on an Open Area Test Site to assert correlation with the chamber measurements per the requirements of KDB 474788 D01.

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#### **MEASUREMENT UNCERTAINTY** 4.0

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.4-2014. All measurement uncertainty values are shown with a coverage factor of k = 2 to indicate a 95% level of confidence. The measurement uncertainty shown below meets or exceeds the  $U_{CISPR}$  measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty (±dB)
Conducted Bench Top Measurements	1.13
Radiated Disturbance (<1GHz)	4.98
Radiated Disturbance (>1GHz)	5.07
Radiated Disturbance (>18GHz)	5.09

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#### TEST EQUIPMENT CALIBRATION DATA 5.0

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST). Measurements antennas used during testing were calibrated in accordance to the requirements of ANSI C63.5-2017.

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	AP1	EMC Cable and Switch System	3/9/2021	Annual	3/9/2022	AP1
-	ETS	EMC Cable and Switch System	3/4/2021	Annual	3/4/2022	ETS
-	LTx4	Licensed Transmitter Cable Set	3/12/2021	Annual	3/12/2022	LTx4
-	LTx5	Licensed Transmitter Cable Set	3/3/2021	Annual	3/3/2022	LTx5
Agilent	N9030A	50GHz PXA Signal Analyzer	1/20/2021	Annual	1/20/2022	US51350301
Anritsu	MT8821C	Radio Communication Analyzer		N/A		6201381794
Anritsu	MT8821C	Radio Communication Analyzer		N/A		6200901190
Emco	3115	Horn Antenna (1-18GHz)	6/18/2020	Biennial	6/18/2022	9704-5182
Emco	3116	Horn Antenna (18 - 40GHz)	8/7/2018	Triennial	8/7/2021	9203-2178
Espec	ESX-2CA	Environmental Chamber	8/27/2020	Annual	8/27/2022	17620
ETS Lindgren	3164-08	Quad Ridge Horn Antenna	3/12/2020	Biennial	3/12/2022	128337
ETS Lindgren	3816/2NM	LISN	7/9/2020	Biennial	7/9/2022	00114451
Keysight Technologies	N9020A	MXA Signal Analyzer	9/22/2020	Annual	9/22/2021	MY54500644
Keysight Technologies	N9030A	PXA Signal Analyzer (44GHz)	8/17/2020	Annual	8/17/2021	MY52350166
Keysight Technologies	N9030A	PXA Signal Analyzer	10/16/2020	Annual	10/16/2021	MY54490576
Keysight Technologies	N9030A	PXA Signal Analyzer	9/2/2020	Annual	9/2/2021	MY55410501
Keysight Technologies	N9038A	MXE EMI Receiver	8/11/2020	Annual	8/11/2021	MY51210133
Mini-Circuits	SSG-4000HP	Synthesized Signal Generator		N/A		11208010032
Mini-Circuits	SSG-4000HP	Synthesized Signal Generator	N/A		11403100002	
Rohde & Schwarz	CMW500	Radio Communication Tester	N/A		112347	
Rohde & Schwarz	ESU40	EMI Test Receiver (40GHz)	9/9/2020	Annual	9/9/2021	100348
Rohde & Schwarz	FSW26	2Hz-26.5GHz Signal and Spectrum Analyzer	2/10/2021	Annual	2/10/2022	103187
Rohde & Schwarz	FSW67	Signal / Spectrum Analyzer	8/10/2020	Annual	8/10/2021	103200

Table 5-1. Summary of Test Results

#### Notes:

- 1. For equipment listed above that has a calibration date or calibration due date that falls within the test date range, care was taken to ensure that this equipment was used after the calibration date and before the calibration due date.
- 2. Equipment with a calibration date of "N/A" shown in this list was not used to make direct calibrated measurements.

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#### SAMPLE CALCULATIONS 6.0

### **Emission Designator**

#### **QPSK Modulation**

**Emission Designator = 8M62G7D** 

LTE BW = 8.62 MHzG = Phase Modulation 7 = Quantized/Digital Info D = Data transmission, telemetry, telecommand

#### **QAM Modulation**

Emission Designator = 8M45W7D

LTE BW = 8.45 MHzW = Amplitude/Angle Modulated 7 = Quantized/Digital Info D = Data transmission, telemetry, telecommand

### **Spurious Radiated Emission – LTE Band**

Example: Middle Channel LTE Mode 2<sup>nd</sup> Harmonic (1564 MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was -81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of -81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 1564 MHz. So 6.1 dB is added to the signal generator reading of -30.9 dBm yielding -24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm - (-24.80).

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## 7.0 TEST RESULTS

## 7.1 Summary

Company Name: <u>Samsung Electronics Co., Ltd.</u>

FCC ID: <u>A3LSMF711JPN</u>

FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)

Mode(s): <u>LTE</u>

Test Condition	Test Description	FCC Part Section(s)	RSS Section(s)	Test Limit	Test Result	Reference
_	Occupied Bandwidth	2.1049	RSS-Gen(6.7)	N/A	PASS	Section 7.2
	Conducted Band Edge / Spurious Emissions	2.1051, 27.53	RSS-139(6.6)	> 43 + 10log10(P[Watts]) at Band Edge and for all out-of- band emissions	PASS	Sections 7.3, 7.4
OND	Transmitter Conducted Output Power	2.1046	RSS-139(4.1)	N/A	PASS	See RF Exposure Report
_	Frequency Stability	2.1055, 27.54	RSS-139(6.4)	Fundamental emissions stay within authorized frequency block	PASS	Section 7.8
	Effective Radiated Power / Equivalent Isotropic Radiated Power (LTE Band 12)	27.50(c)(10)	RSS-130(4.4)	< 3 Watts max. ERP < 5 Watts max. EIRP	PASS	Section 7.6
_	Effective Radiated Power / Equivalent Isotropic Radiated Power (LTE Band 13)	27.50(b)(10)	RSS-130(4.4)	< 3 Watts max. ERP < 5 Watts max. EIRP	PASS	Section 7.6
	Equivalent Isotropic Radiated Power (LTE Band 4)	27.50(d)(4)	RSS-139(6.5)	< 1 Watts max. EIRP	PASS	Section 7.6
RAI	Radiated Spurious Emissions (LTE Band 13)	2.1053, 27.53(f)	RSS-139(6.6)	< -70 dBW/MHz (for wideband signals) < -80 dBW (for discrete emissions less than 700Hz BW) For all emissions in the band 1559 - 1610 MHz	PASS	Section 7.7
	Radiated Spurious Emissions	2.1053, 27.53	RSS-139(6.6)	> 43 + 10 log10 (P[Watts]) for all out-of-band emissions	PASS	Section 7.7

Table 7-1. Summary of Test Results

### Notes:

- 1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
- 2) The analyzer plots shown in Section 7.0 were taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
- 3) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
- 4) For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST 2G/3G Automation Version 4.2.

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### 7.2 Occupied Bandwidth

### **Test Overview**

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

#### **Test Procedure Used**

KDB 971168 D01 v03r01 - Section 4.2

### **Test Settings**

- 1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
- 2. RBW = 1 5% of the expected OBW
- 3. VBW  $\geq$  3 x RBW
- 4. Detector = Peak
- 5. Trace mode = max hold
- 6. Sweep = auto couple
- 7. The trace was allowed to stabilize
- 8. If necessary, steps 2-7 were repeated after changing the RBW such that it would be within
  - 1 5% of the 99% occupied bandwidth observed in Step 7

### **Test Setup**

The EUT and measurement equipment were set up as shown in the diagram below.



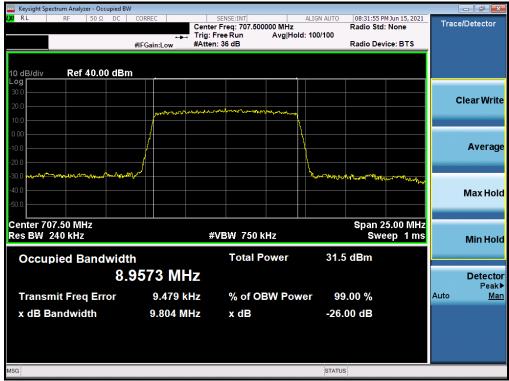
Figure 7-1. Test Instrument & Measurement Setup

#### **Test Notes**

None.

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Plot 7-1. Occupied Bandwidth Plot (LTE Band 12 - 10MHz QPSK - Full RB)



Plot 7-2. Occupied Bandwidth Plot (LTE Band 12 - 10MHz 16-QAM - Full RB)

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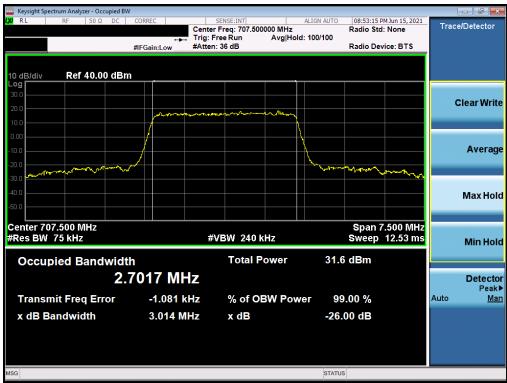
Plot 7-3. Occupied Bandwidth Plot (LTE Band 12 - 5MHz QPSK - Full RB)



Plot 7-4. Occupied Bandwidth Plot (LTE Band 12 - 5MHz 16-QAM - Full RB)

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Plot 7-5. Occupied Bandwidth Plot (LTE Band 12 - 3MHz QPSK - Full RB)



Plot 7-6. Occupied Bandwidth Plot (LTE Band 12 - 3MHz 16-QAM - Full RB)

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Plot 7-7. Occupied Bandwidth Plot (LTE Band 12 – 1.4MHz QPSK - Full RB)



Plot 7-8. Occupied Bandwidth Plot (LTE Band 12 - 1.4MHz 16-QAM - Full RB)

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Plot 7-9. Occupied Bandwidth Plot (LTE Band 13 - 10MHz QPSK - Full RB)



Plot 7-10. Occupied Bandwidth Plot (LTE Band 13 - 10MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-11. Occupied Bandwidth Plot (LTE Band 13 - 5MHz QPSK - Full RB)



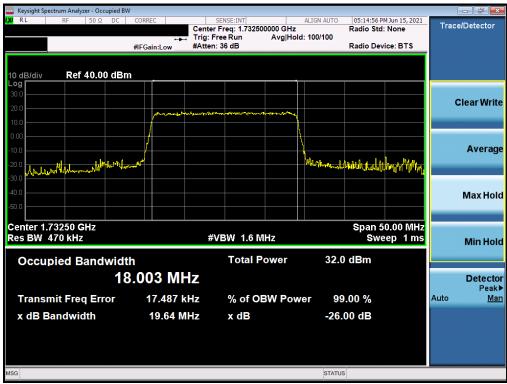
Plot 7-12. Occupied Bandwidth Plot (LTE Band 13 - 5MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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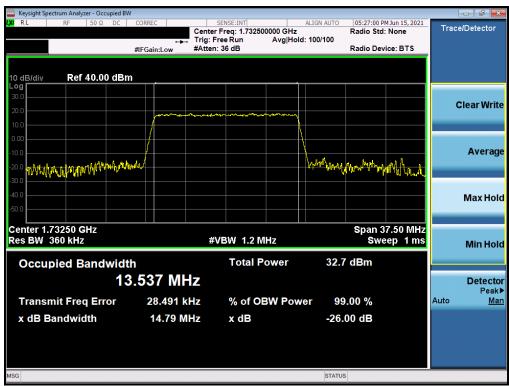
Plot 7-13. Occupied Bandwidth Plot (LTE Band 4 - 20MHz QPSK - Full RB)



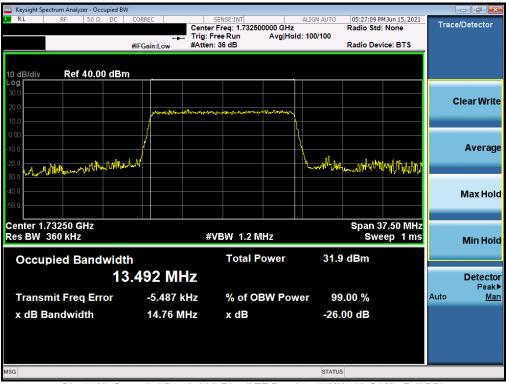
Plot 7-14. Occupied Bandwidth Plot (LTE Band 4 - 20MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Poud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-15. Occupied Bandwidth Plot (LTE Band 4 - 15MHz QPSK - Full RB)



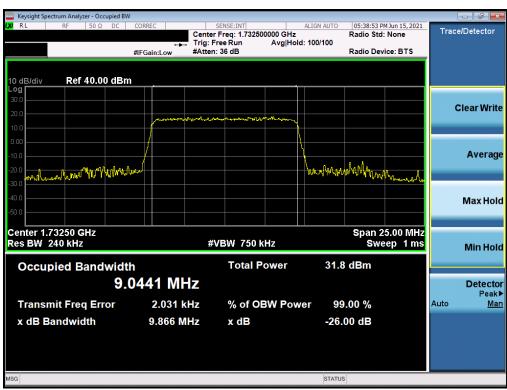
Plot 7-16. Occupied Bandwidth Plot (LTE Band 4 - 15MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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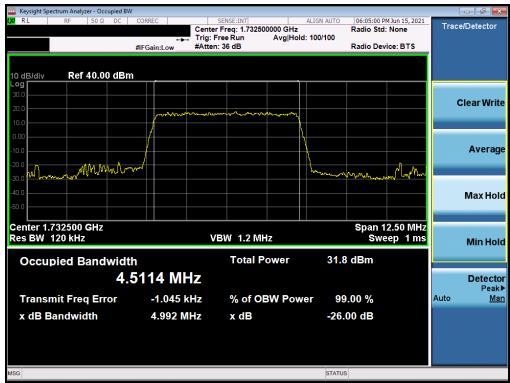
Plot 7-17. Occupied Bandwidth Plot (LTE Band 4 - 10MHz QPSK - Full RB)



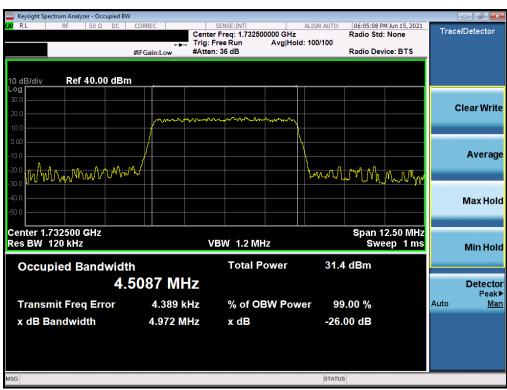
Plot 7-18. Occupied Bandwidth Plot (LTE Band 4 - 10MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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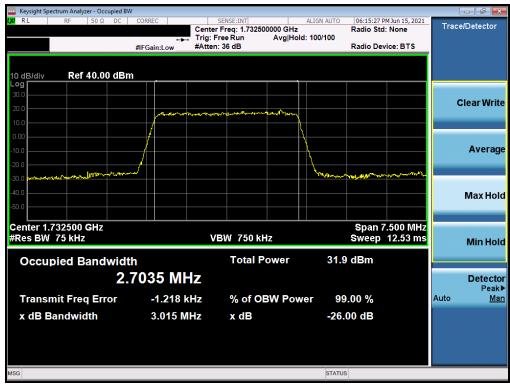
Plot 7-19. Occupied Bandwidth Plot (LTE Band 4 - 5MHz QPSK - Full RB)



Plot 7-20. Occupied Bandwidth Plot (LTE Band 4 - 5MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-21. Occupied Bandwidth Plot (LTE Band 4 - 3MHz QPSK - Full RB)



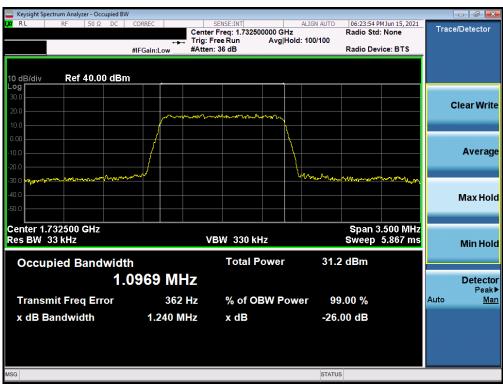
Plot 7-22. Occupied Bandwidth Plot (LTE Band 4 - 3MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-23. Occupied Bandwidth Plot (LTE Band 4 - 1.4MHz QPSK - Full RB)



Plot 7-24. Occupied Bandwidth Plot (LTE Band 4 - 1.4MHz 16-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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## 7.3 Spurious and Harmonic Emissions at Antenna Terminal

#### **Test Overview**

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10<sup>th</sup> harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is 43 + 10  $log_{10}(P_{[Watts]})$ , where P is the transmitter power in Watts.

#### **Test Procedure Used**

KDB 971168 D01 v03r01 - Section 6.0

#### **Test Settings**

- 1. Start frequency was set to 30MHz and stop frequency was set to 18GHz (separated into at least two plots per channel)
- 2. RBW ≥ 100kHz
- 3. VBW ≥ 3 x RBW
- 4. Detector = RMS
- 5. Trace mode = max hold
- 6. Sweep time = auto couple
- 7. The trace was allowed to stabilize

### **Test Setup**

The EUT and measurement equipment were set up as shown in the diagram below.



Figure 7-2. Test Instrument & Measurement Setup

#### **Test Notes**

Per Part 27 and RSS-139, compliance with the applicable limits is based on the use of measurement instrumentation employing a resolution bandwidth 100 kHz or greater for measurements below 1GHz. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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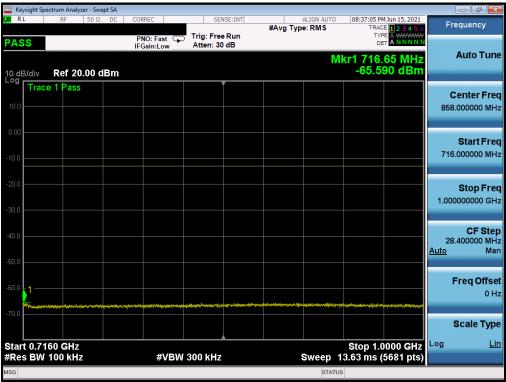
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Plot 7-25. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - Low Channel)

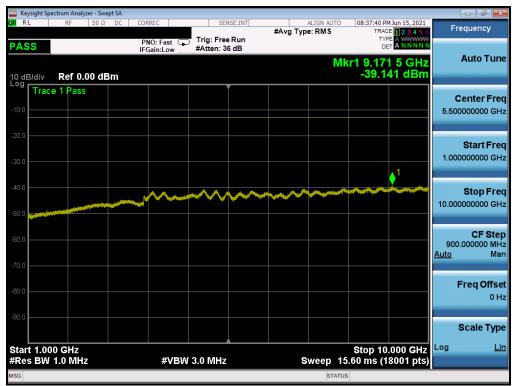


Plot 7-26. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - Low Channel)

FCC ID: A3LSMF711JPN	Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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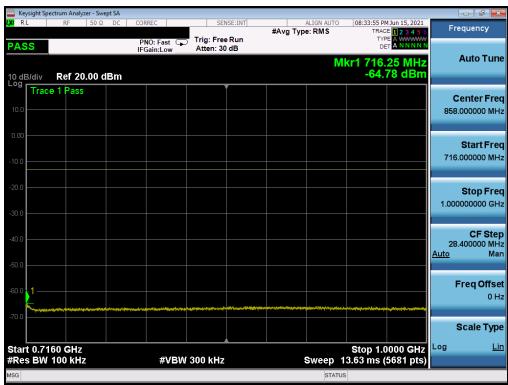
Plot 7-27. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - Low Channel)



Plot 7-28. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - Mid Channel)

FCC ID: A3LSMF711JPN	Provide to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
Test Report S/N:	Test Dates:	EUT Type:		Dago 26 of 90
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Plot 7-29. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - Mid Channel)



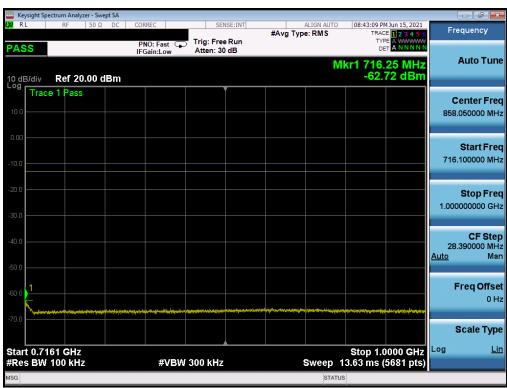
Plot 7-30. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - Mid Channel)

FCC ID: A3LSMF711JPN	PCTEST* Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-31. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - High Channel )



Plot 7-32. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - High Channel)

FCC ID: A3LSMF711JPN	Pout to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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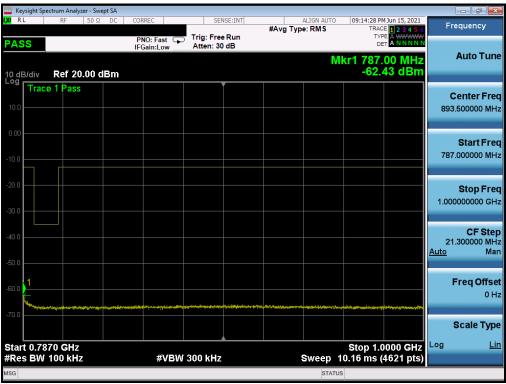
Plot 7-33. Conducted Spurious Plot (LTE Band 12 - 10MHz QPSK - 1 RB - High Channel)

FCC ID: A3LSMF711JPN	Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-34. Conducted Spurious Plot (LTE Band 13 - 10MHz QPSK - 1 RB)



Plot 7-35. Conducted Spurious Plot (LTE Band 13 - 10MHz QPSK - 1 RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-36. Conducted Spurious Plot (LTE Band 13 - 10MHz QPSK - 1 RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager	
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Plot 7-37. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - Low Channel)



Plot 7-38. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - Low Channel)

FCC ID: A3LSMF711JPN	Poud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager	
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Plot 7-39. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - Low Channel)



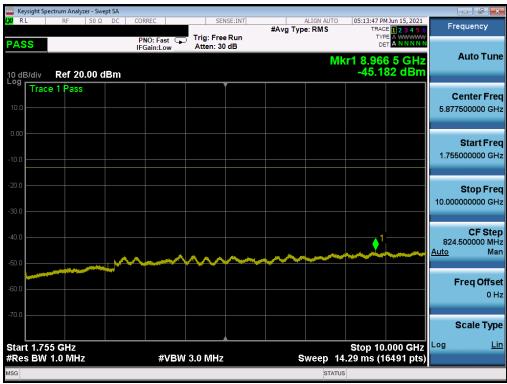
Plot 7-40. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - Mid Channel)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager	
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Plot 7-41. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - Mid Channel)



Plot 7-42. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - Mid Channel)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager	
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Plot 7-43. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - High Channel)



Plot 7-44. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - High Channel)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager	
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Plot 7-45. Conducted Spurious Plot (LTE Band 4 - 20MHz QPSK - 1 RB - High Channel)

FCC ID: A3LSMF711JPN	Poud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager	
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### 7.4 Band Edge Emissions at Antenna Terminal

#### **Test Overview**

All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at its maximum duty cycle, at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is  $43 + 10 \log_{10}(P_{[Watts]})$ , where P is the transmitter power in Watts.

### **Test Procedure Used**

KDB 971168 D01 v03r01 - Section 6.0

## **Test Settings**

- 1. Start and stop frequency were set such that the band edge would be placed in the center of the plot
- 2. Span was set large enough so as to capture all out of band emissions near the band edge
- 3. RBW ≥ 1% of the emission bandwidth
- 4.  $VBW > 3 \times RBW$
- 5. Detector = RMS
- 6. Number of sweep points ≥ 2 x Span/RBW
- 7. Trace mode = trace average for continuous emissions, max hold for pulse emissions
- 8. Sweep time = auto couple
- 9. The trace was allowed to stabilize

### **Test Setup**

The EUT and measurement equipment were set up as shown in the diagram below.



Figure 7-3. Test Instrument & Measurement Setup

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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#### **Test Notes**

Per 27.53(h) in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to demonstrate compliance with the out-of-band emissions limit. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

Per 27.53(g) for operations in the 663 - 698 MHz and 698 - 746MHz bands, in the 100 kHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least 30 kHz may be employed to demonstrate compliance with the out-of-band emissions limit.

Per 27.53(c)(5) for operations in the 776-788 MHz band, in the 100 kHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least 30 kHz may be employed to demonstrate compliance with the out-of-band emissions limit.

For all plots showing emissions in the 763 - 775MHz and 793 - 805MHz band, the FCC limit per 27.53(c)(4) is  $65 + 10 \log_{10}(P) = -35$ dBm in a 6.25kHz bandwidth.

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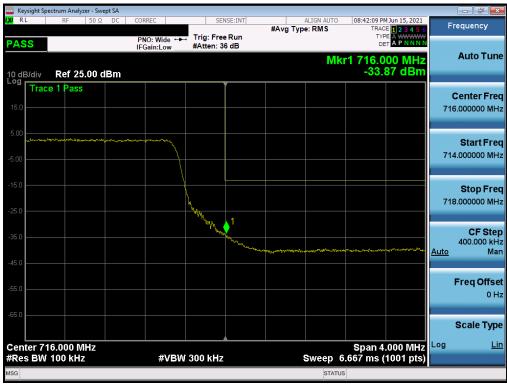
assembly of contents thereof, please contact INFO@PCTEST.COM.



### LTE Band 12 -



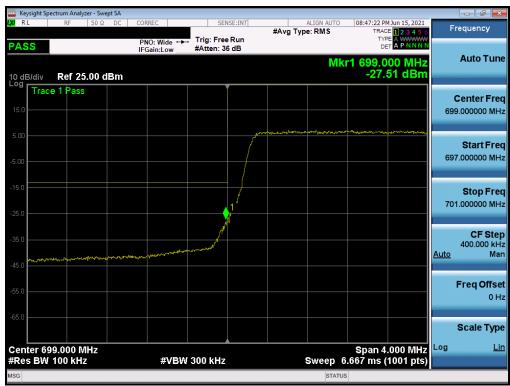
Plot 7-46. Lower Band Edge Plot (LTE Band 12 - 10MHz QPSK - Full RB)



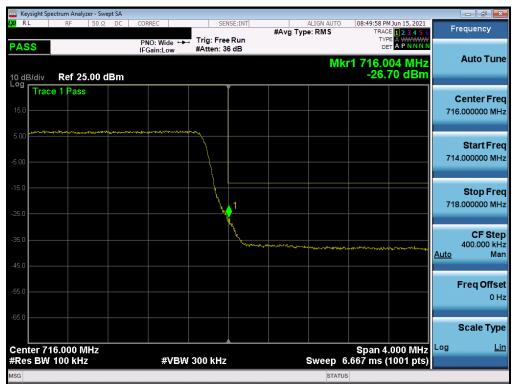
Plot 7-47. Upper Band Edge Plot (LTE Band 12 - 10MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Pout to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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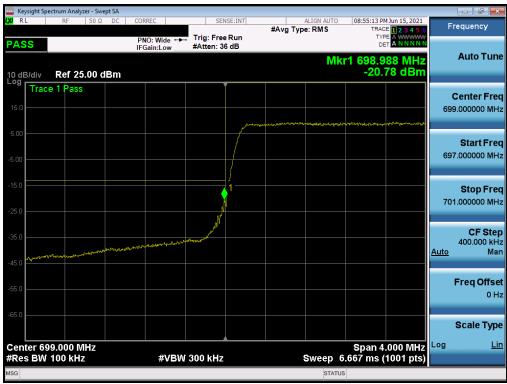
Plot 7-48. Lower Band Edge Plot (LTE Band 12 - 5MHz QPSK - Full RB)



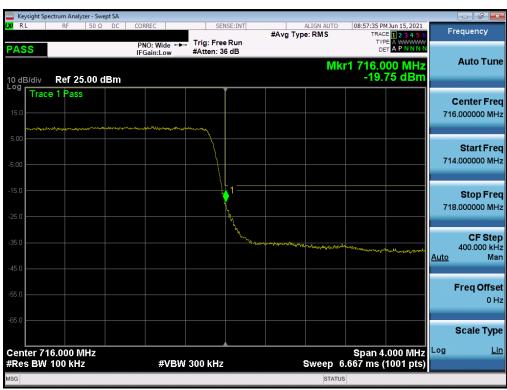
Plot 7-49. Upper Band Edge Plot (LTE Band 12 - 5MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-50. Lower Band Edge Plot (LTE Band 12 - 3MHz QPSK - Full RB)



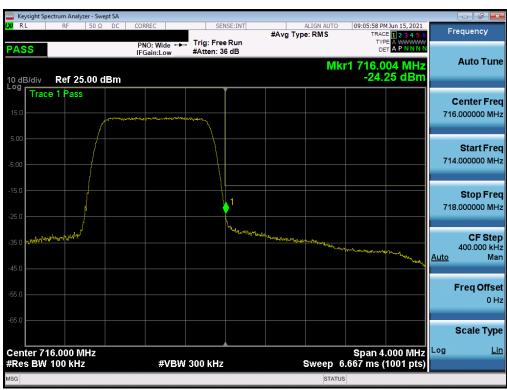
Plot 7-51. Upper Band Edge Plot (LTE Band 12 - 3MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Pout to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-52. Lower Band Edge Plot (LTE Band 12 - 1.4MHz QPSK - Full RB)



Plot 7-53. Upper Band Edge Plot (LTE Band 12 - 1.4MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### LTE Band 13



Plot 7-54. Lower Band Edge Plot (LTE Band 13 - 10MHz QPSK - Full RB)



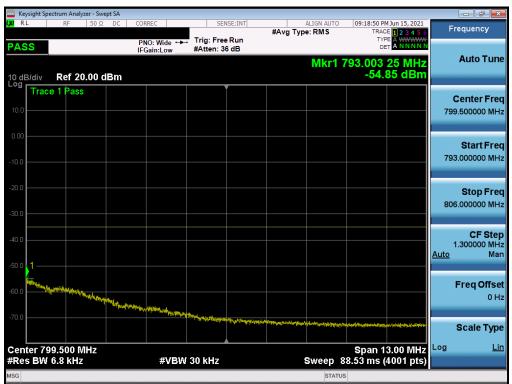
Plot 7-55. Lower Emission Mask Plot (LTE Band 13 - 10MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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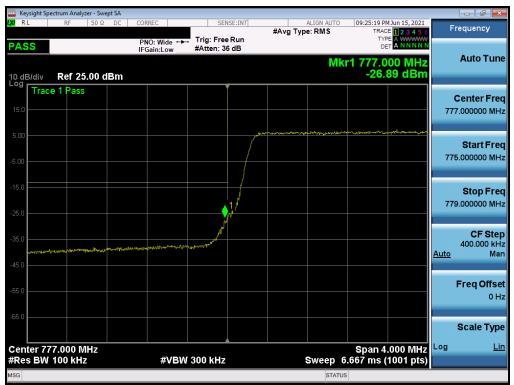
Plot 7-56. Upper Band Edge Plot (LTE Band 13 - 10MHz QPSK - Full RB)



Plot 7-57. Upper Emission Mask Plot (LTE Band 13 - 10MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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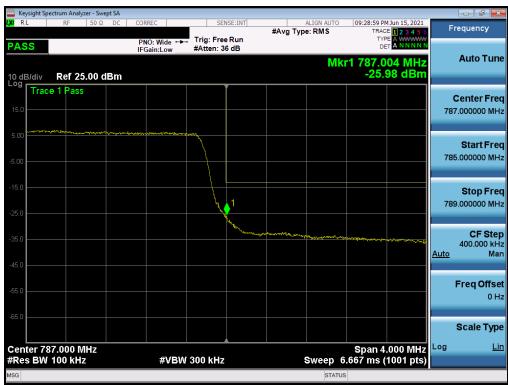
Plot 7-58. Lower Band Edge Plot (LTE Band 13 - 5MHz QPSK - Full RB)



Plot 7-59. Lower Emission Mask Plot (LTE Band 13 - 5MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-60. Upper Band Edge Plot (LTE Band 13 - 5MHz QPSK - Full RB)



Plot 7-61. Upper Emission Mask Plot (LTE Band 13 - 5MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Pout to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### LTE Band 4



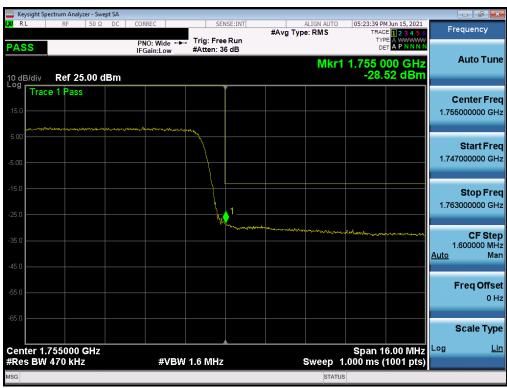
Plot 7-62. Lower Band Edge Plot (LTE Band 4 - 20MHz QPSK - Full RB)



Plot 7-63. Lower Extended Band Edge Plot (LTE Band 4 - 20MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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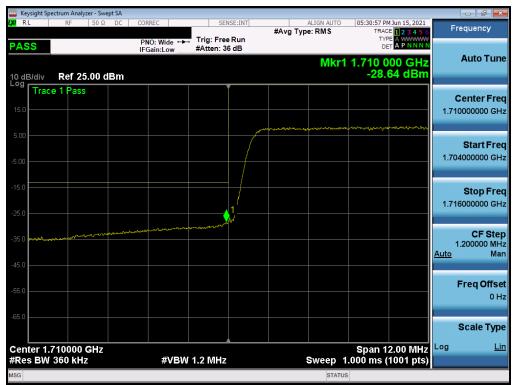
Plot 7-64. Upper Band Edge Plot (LTE Band 4 - 20MHz QPSK - Full RB)



Plot 7-65. Upper Extended Band Edge Plot (LTE Band 4 - 20MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Pout to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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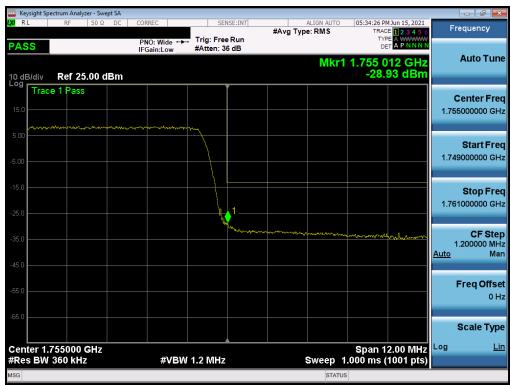
Plot 7-66. Lower Band Edge Plot (LTE Band 4 - 15MHz QPSK - Full RB)



Plot 7-67. Lower Extended Band Edge Plot (LTE Band 4 - 15MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-68. Upper Band Edge Plot (LTE Band 4 - 15MHz QPSK - Full RB)



Plot 7-69. Upper Extended Band Edge Plot (LTE Band 4 - 15MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-70. Lower Band Edge Plot (LTE Band 4 - 10MHz QPSK - Full RB)



Plot 7-71. Lower Extended Band Edge Plot (LTE Band 4 - 10MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
Test Report S/N:	Test Dates:	EUT Type:		Page 51 of 80
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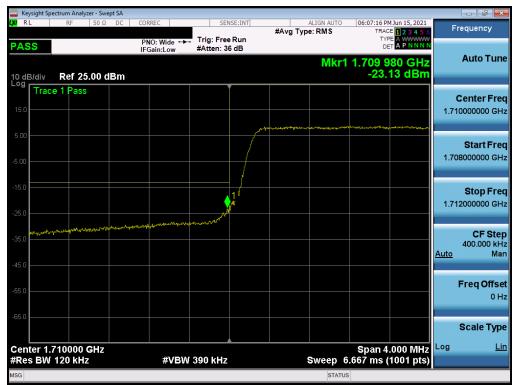
Plot 7-72. Upper Band Edge Plot (LTE Band 4 - 10MHz QPSK - Full RB)



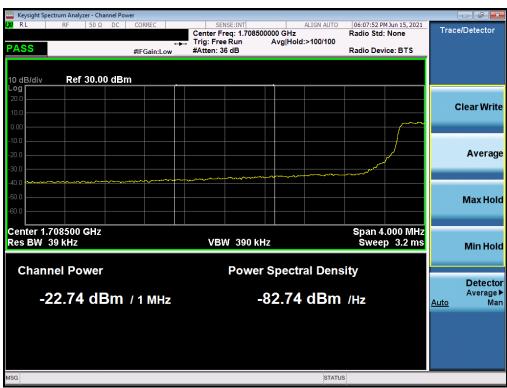
Plot 7-73. Upper Extended Band Edge Plot (LTE Band 4 - 10MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-74. Lower Band Edge Plot (LTE Band 4 - 5MHz QPSK - Full RB)



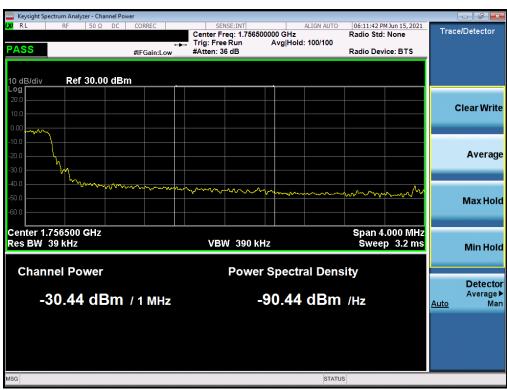
Plot 7-75. Lower Extended Band Edge Plot (LTE Band 4 - 5MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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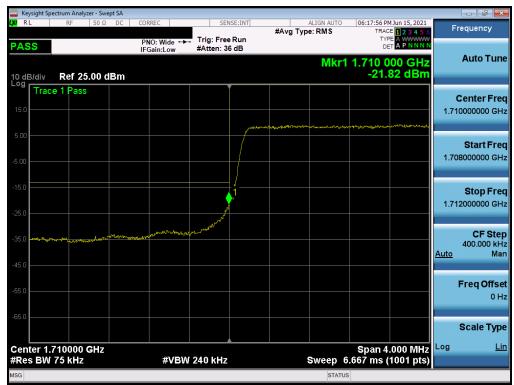
Plot 7-76. Upper Band Edge Plot (LTE Band 4 - 5MHz QPSK - Full RB)



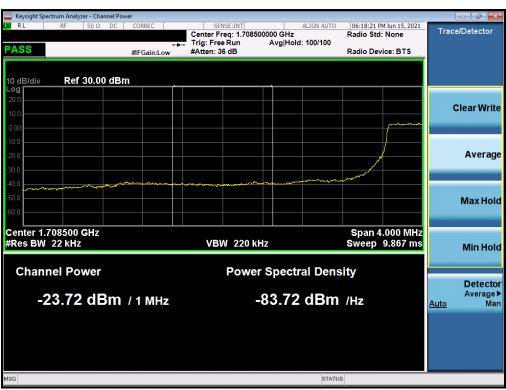
Plot 7-77. Upper Extended Band Edge Plot (LTE Band 4 - 5MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	PCTEST* Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
Test Report S/N:	Test Dates:	EUT Type:		Dogo 54 of 90
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Plot 7-78. Lower Band Edge Plot (LTE Band 4 - 3MHz QPSK - Full RB)



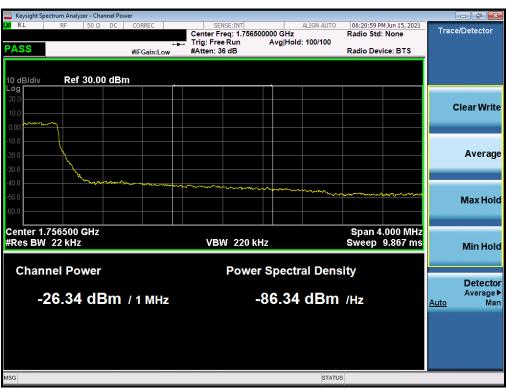
Plot 7-79. Lower Extended Band Edge Plot (LTE Band 4 - 3MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
Test Report S/N:	Test Dates:	EUT Type:		Page 55 of 80
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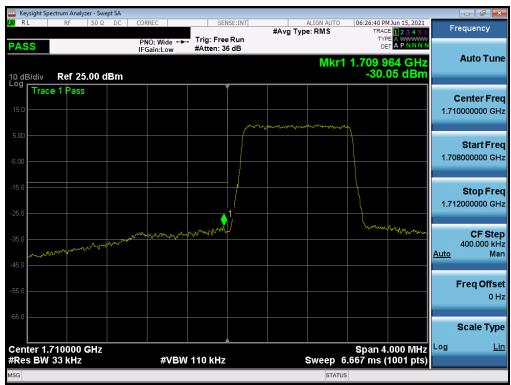
Plot 7-80. Upper Band Edge Plot (LTE Band 4 - 3MHz QPSK - Full RB)



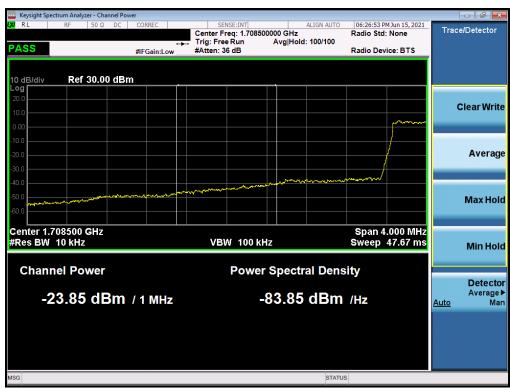
Plot 7-81. Upper Extended Band Edge Plot (LTE Band 4 - 3MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of @ element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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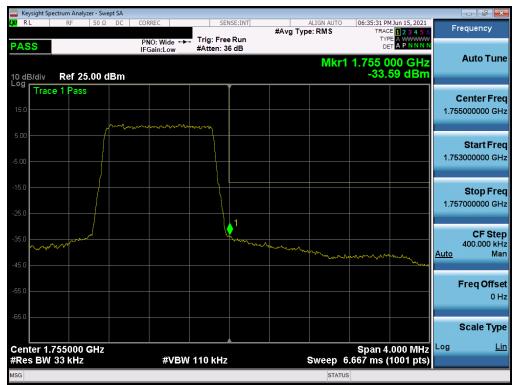
Plot 7-82. Lower Band Edge Plot (LTE Band 4 – 1.4MHz QPSK – Full RB)



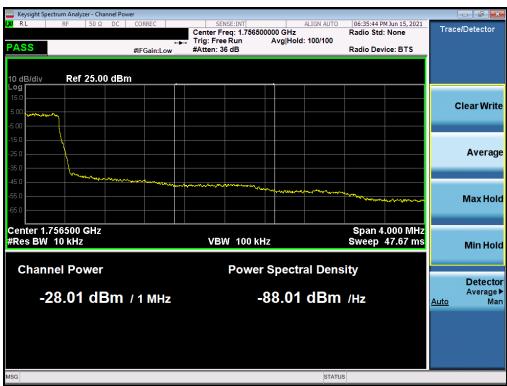
Plot 7-83. Lower Extended Band Edge Plot (LTE Band 4 - 1.4MHz QPSK - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-84. Upper Band Edge Plot (LTE Band 4 – 1.4MHz QPSK – Full RB)



Plot 7-85. Upper Extended Band Edge Plot (LTE Band 4 – 1.4MHz QPSK – Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### 7.5 Peak-Average Ratio

### **Test Overview**

A peak to average ratio measurement is performed at the conducted port of the EUT. The spectrum analyzers Complementary Cumulative Distribution Function (CCDF) measurement profile is used to determine the largest deviation between the average and the peak power of the EUT in a given bandwidth. The CCDF curve shows how much time the peak waveform spends at or above a given average power level. The percent of time the signal spends at or above the level defines the probability for that particular power level.

#### **Test Procedure Used**

KDB 971168 D01 v03r01 - Section 5.7.1

### **Test Settings**

- 1. The signal analyzer's CCDF measurement profile is enabled
- 2. Frequency = carrier center frequency
- 3. Measurement BW ≥ OBW or specified reference bandwidth
- 4. The signal analyzer was set to collect one million samples to generate the CCDF curve
- 5. The measurement interval was set depending on the type of signal analyzed. For continuous signals (>98% duty cycle), the measurement interval was set to 1ms. For burst transmissions, the spectrum analyzer is set to use an internal "RF Burst" trigger that is synced with an incoming pulse and the measurement interval is set to less than the duration of the "on time" of one burst to ensure that energy is only captured during a time in which the transmitter is operating at maximum power

### **Test Setup**

The EUT and measurement equipment were set up as shown in the diagram below.



Figure 7-4. Test Instrument & Measurement Setup

#### **Test Notes**

None.

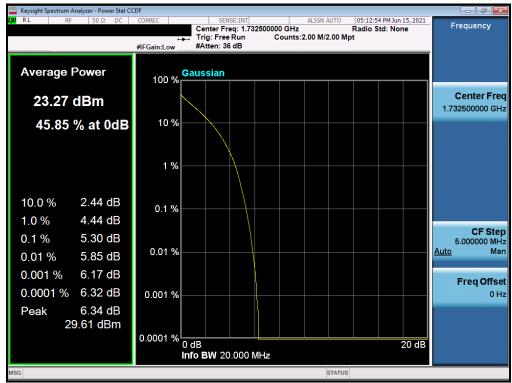
FCC ID: A3LSMF711JPN	Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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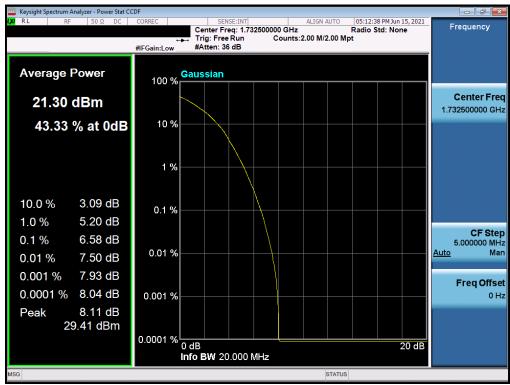
V2.0 4/5/2021
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#### LTE Band 4 -



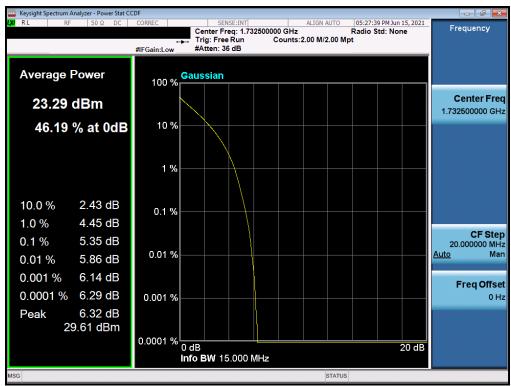
Plot 7-86. PAR Plot (LTE Band 4 - 20MHz QPSK - Full RB)



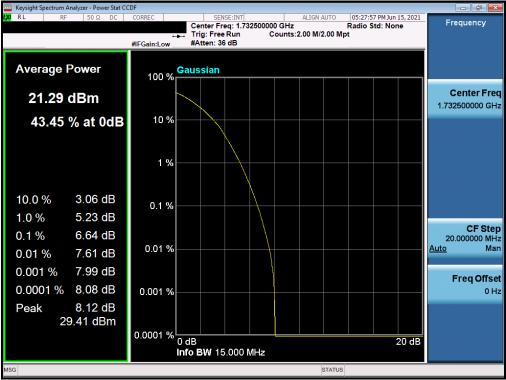
Plot 7-87. PAR Plot (LTE Band 4 - 20MHz 64-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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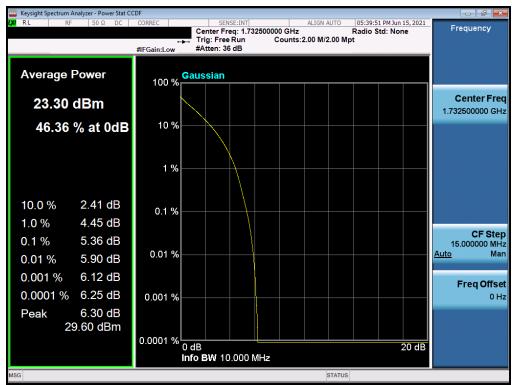
Plot 7-88. PAR Plot (LTE Band 4 - 15MHz QPSK - Full RB)



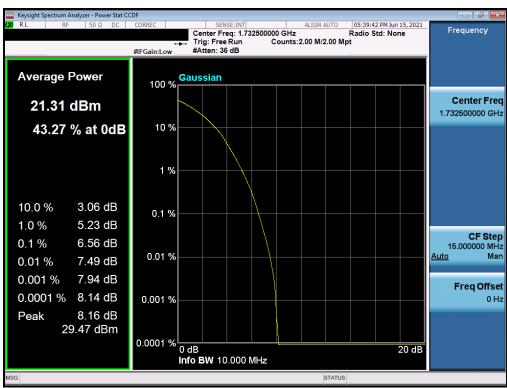
Plot 7-89. PAR Plot (LTE Band 4 - 15MHz 64-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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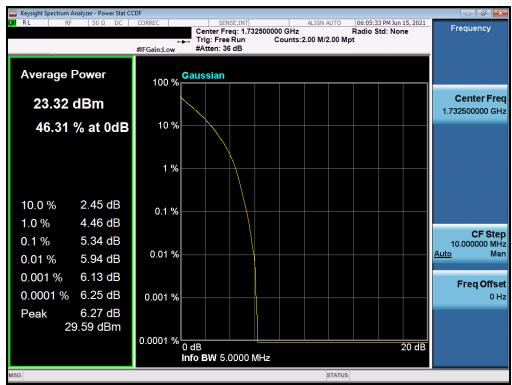
Plot 7-90. PAR Plot (LTE Band 4 - 10MHz QPSK - Full RB)



Plot 7-91. PAR Plot (LTE Band 4 - 10MHz 64-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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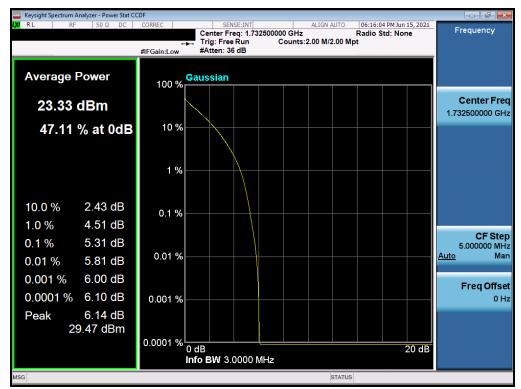
Plot 7-92. PAR Plot (LTE Band 4 - 5MHz QPSK - Full RB)



Plot 7-93. PAR Plot (LTE Band 4 - 5MHz 64-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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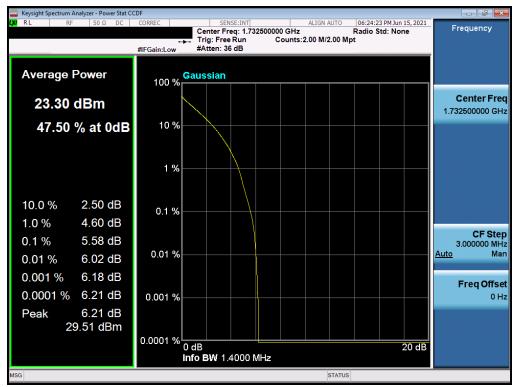
Plot 7-94. PAR Plot (LTE Band 4 - 3MHz QPSK - Full RB)



Plot 7-95. PAR Plot (LTE Band 4 - 3MHz 64-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Plot 7-96. PAR Plot (LTE Band 4 - 1.4MHz QPSK - Full RB)



Plot 7-97. PAR Plot (LTE Band 4 - 1.4MHz 64-QAM - Full RB)

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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#### 7.6 Radiated Power (ERP/EIRP)

### **Test Overview**

Effective Radiated Power (ERP) and Equivalent Isotropic Radiated Power (EIRP) measurements are performed using the substitution method described in ANSI/TIA-603-E-2016 with the EUT transmitting into an integral antenna. Measurements on signals operating below 1GHz are performed using vertically and horizontally polarized tuned dipole antennas. Measurements on signals operating above 1GHz are performed using vertically and horizontally polarized broadband horn antennas. All measurements are performed as RMS average measurements while the EUT is operating at maximum power, and at the appropriate frequencies.

### **Test Procedures Used**

KDB 971168 D01 v03r01 - Section 5.2.1

ANSI/TIA-603-E-2016 - Section 2.2.17

#### **Test Settings**

- 1. Radiated power measurements are performed using the signal analyzer's "channel power" measurement capability for signals with continuous operation.
- 2. RBW = 1 5% of the expected OBW, not to exceed 1MHz
- 3. VBW ≥ 3 x RBW
- 4. Span = 1.5 times the OBW
- 5. No. of sweep points > 2 x span / RBW
- 6. Detector = RMS
- 7. Trigger is set to "free run" for signals with continuous operation with the sweep times set to "auto".
- 8. The integration bandwidth was roughly set equal to the measured OBW of the signal for signals with continuous operation.
- 9. Trace mode = trace averaging (RMS) over 100 sweeps
- 10. The trace was allowed to stabilize

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### **Test Setup**

The EUT and measurement equipment were set up as shown in the diagram below.

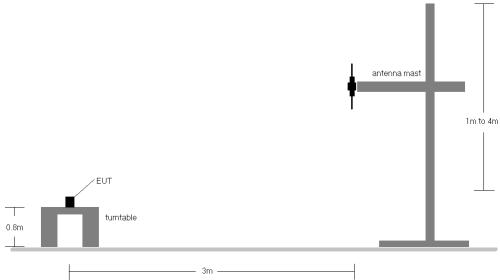


Figure 7-5. Radiated Test Setup <1GHz

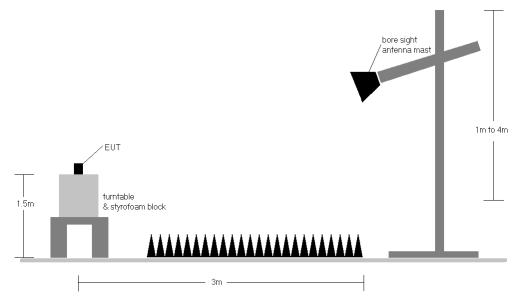


Figure 7-6. Radiated Test Setup >1GHz

### **Test Notes**

- 1) The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The worst case emissions are reported with the EUT positioning, modulations, RB sizes and offsets, and channel bandwidth configurations shown in the tables below.
- 2) This unit was tested with its standard battery.

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Bandwidth	Mod.	Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Ant. Gain [dBi]	RB Size/Offset	Substitute Level [dBm]	EIRP [dBm]	EIRP [Watts]	EIRP Limit [dBm]	Margin [dB]	ERP [dBm]	ERP [Watts]	ERP Limit [dBm]	Margin [dB]
N		704.0	н	112	165	3.48	1 / 49	14.07	17.55	0.057	36.99	-19.44	15.40	0.035	34.77	-19.37
갶	QPSK	707.5	H	101	173	3,52	1 / 49	14.76	18.28	0.067	36.99	-18.71	16.13	0.041	34.77	-18.64
0	10.00	711.0	H	101	175	3,57	1 / 25	14.62	18.19	0.066	36.99	-18,80	16.04	0.040	34.77	-18.73
-	16-QAM	707.5	H	101	173	3.52	1 / 49	14.30	17.82	0.061	36.99	-19.17	15.67	0.037	34.77	-19.10
24		701.5	H	112	165	3.45	1 / 24	13.84	17.29	0.054	36.99	-19.70	15.14	0.033	34.77	-19.63
MHz	QPSK	707.5	H	101	173	3.52	1 / 24	14.71	18.24	0.067	36.99	-18.75	16.09	0.041	34.77	-18.69
2 ≤		713.5	H	101	175	3.70	1/0	14.75	18.45	0.070	36.99	-18.54	16.30	0.043	34.77	-18.47
	16-QAM	707.5	н	101	173	3.52	1/24	14.23	17.76	0.060	36.99	-19.23	15.61	0.036	34.77	-19.17
		700.5	H	112	165	3.39	1/0	13.91	17.30	0.054	36.99	-19.69	15.15	0.033	34.77	-19.62
MHZ	QPSK	707.5	н	101	173	3.52	1/7	14.71	18.23	0.067	36.99	-18.76	16.08	0.041	34.77	-18.69
3 ₹	12.4	714.5	H	101	175	3.71	1/0	14.58	18.29	0.067	36.99	-18.70	16.14	0.041	34.77	-18.63
	16-QAM	707.5	H	101	173	3.52	1/7	14.22	17.74	0.059	36.99	-19.25	15.59	0.036	34.77	-19.18
N		699.7	H	112	165	3.33	1/3	14.09	17.42	0.055	36.99	-19.57	15.27	0.034	34.77	-19.50
MHz	QPSK	707.5	. н .	101	173	3.52	1/3	14.79	18.32	0.068	36.99	-18.67	16.17	0.041	34.77	-18.60
4		715.3	н	101	175	3.72	1/3	14.47	18.18	0.066	36.99	-18.80	16.03	0.040	34.77	-18.74
<del>-</del>	16-QAM	707.5	н	101	173	3.52	1/3	14.40	17.92	0.062	36.99	-19.07	15.77	0.038	34.77	-19.00
	Opposite Pol.	707.5	V	153	351	3.62	1/5	14.48	18.10	0.065	36.99	-18.89	15.95	0.039	34.77	-18.82
10 MHz	Opposite Pol (HALF)	707.5	H	281	220	3.52	1/3	14.48	18.00	0.063	36.99	-18.99	15.85	0.038	34.77	-18.92
	WCP	707.5	н	101	173	3.52	1/5	13.67	17.19	0.052	36.99	-19.80	15.04	0.032	34.77	-19.73

## Table 7-2. ERP Data (LTE Band 12 - Open)

Bandwidth	Mod.	Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Ant. Gain [dBi]	RB Size/Offset	Substitute Level [dBm]	EIRP [dBm]	EIRP [Watts]	EIRP Limit [dBm]	Margin [dB]	ERP [dBm]	ERP [Watts]	ERP Limit [dBm]	Margin [dB]
MHz	QPSK	782.0	٧	153	234	5.99	1 / 49	13.02	19.01	0.080	36.99	-17.98	16.86	0.049	34.77	-17.91
5	16-QAM	782.0	V	153	234	5.99	1/49	12.43	18.42	0.070	36.99	-18.57	16.27	0.042	34.77	-18.50
-		779.5	V	153	234	5,97	1/24	13.22	19.19	0.083	36.99	-17.80	17.04	0.051	34.77	-17.73
보	QPSK	782.0	V	153	234	5,99	1 / 12	12.89	18.88	0.077	36.99	-18.11	16.73	0.047	34,77	-18.04
5 MF		784.5	V	153	234	6.07	1/0	13.00	19.07	0.081	36.99	-17.92	16.92	0.049	34.77	-17.85
47	16-QAM	779.5	V	153	234	5.97	1/24	12.92	18.88	0.077	36.99	-18.11	16.73	0.047	34,77	-18.04
	Opposite Pol	782.0	Н	250	279	6.09	1/0	12.89	18.98	0,079	36.99	-18.01	16.83	0.048	34.77	-17.94
10 MHz	Opposite Pol (HALF)	782.0	Н	213	46	6.09	1/24	11.97	18.06	0.064	36.99	-18.93	15.91	0.039	34,77	-18.86
	WCP	782.0	V	153	234	5.99	1/0	1.63	7.62	0.006	36.99	-29.37	5.47	0.004	34.77	-29.30

## Table 7-3. ERP Data (LTE Band 13 - Open)

Bandwidth	Mod.	Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Ant. Gain [dBi]	RB Size/Offset	Substitute Level [dBm]	EIRP [dBm]	EIRP [Watts]	EIRP Limit [dBm]	Margin [dB]
		1720.0	V	153	321	9.33	1/0	13.37	22.70	0.186	30.00	-7.30
20 MHz	QPSK	1732.5	V	138	323	9.16	1/0	12.35	21.51	0.141	30.00	-8.49
ZU WITZ		1745.0	V	123	317	9.03	1 / 50	11.16	20.19	0.105	30.00	-9.81
	16-QAM	1720.0	V	153	321	9.33	1/0	12.47	21.80	0.151	30.00	-8.20
		1717.5	V	153	321	9.38	1 / 37	13.43	22.81	0.191	30.00	-7.19
15 MHz	QPSK	1732.5	V	138	323	9.16	1 / 37	12.45	21.61	0.145	30.00	-8.39
15 MINZ		1747.5	V	123	317	9.03	1 / 74	11.20	20.24	0.106	30.00	-9.76
	16-QAM	1717.5	V	153	321	9.38	1 / 37	12.66	22.04	0.160	30.00	-7.96
		1715.0	V	153	321	9.42	1 / 25	13.48	22.91	0.195	30.00	-7.09
10 MHz	QPSK	1732.5	V	138	323	9.16	1 / 25	12.57	21.72	0.149	30.00	-8.28
10 MINZ		1750.0	V	123	317	9.03	1 / 25	11.53	20.56	0.114	30.00	-9.44
	16-QAM	1715.0	V	153	321	9.42	1 / 25	12.86	22.28	0.169	30.00	-7.72
		1712.5	V	153	321	9.47	1 / 24	13.52	22.99	0.199	30.00	-7.01
5 MHz	QPSK	1732.5	V	138	323	9.16	1/0	12.47	21.62	0.145	30.00	-8.38
3 MILZ		1752.5	V	123	317	9.05	1/0	11.35	20.39	0.109	30.00	-9.61
	16-QAM	1712.5	V	153	321	9.47	1 / 24	12.55	22.02	0.159	30.00	-7.98
		1711.5	V	153	321	9.49	1 / 14	13.37	22.86	0.193	30.00	-7.14
3 MHz	QPSK	1732.5	V	138	323	9.16	1/7	12.35	21.51	0.141	30.00	-8.49
2 MILZ		1753.5	V	123	317	9.05	1/7	11.55	20.60	0.115	30.00	-9.40
	16-QAM	1711.5	V	153	321	9.49	1 / 14	12.59	22.08	0.161	30.00	-7.92
		1710.7	V	153	321	9.50	1/3	13.30	22.80	0.190	30.00	-7.20
1.4 MHz	QPSK	1732.5	V	138	323	9.16	1/0	12.46	21.61	0.145	30.00	-8.39
1.4 WITZ		1754.3	V	123	317	9.05	1/0	11.17	20.23	0.105	30.00	-9.77
	16-QAM	1710.7	V	153	321	9.50	1/3	12.48	21.98	0.158	30.00	-8.02
	Opposite Pol.	1720.0	Н	128	179	9.47	1 / 99	11.69	21.16	0.131	30.00	-8.84
20 MHz	Opposite Pol. (HALF)	1720.0	Н	188	182	9.47	1 / 99	12.65	22.12	0.163	30.00	-7.88
	WCP	1720.0	V	153	321	9.33	1 / 50	6.95	16.28	0.042	30.00	-13.72

Table 7-4. EIRP Data (LTE Band 4 -Open)

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#### **Radiated Spurious Emissions Measurements** 7.7

### **Test Overview**

Radiated spurious emissions measurements are performed using the substitution method described in ANSI/TIA-603-E-2016 with the EUT transmitting into an integral antenna. Measurements on signals operating below 1GHz are performed using horizontally and vertically polarized tuned dipole antennas. Measurements on signals operating above 1GHz are performed using vertically and horizontally polarized broadband horn antennas. All measurements are performed as RMS measurements while the EUT is operating at maximum power, and at the appropriate frequencies.

### **Test Procedures Used**

KDB 971168 D01 v03r01 - Section 5.8

ANSI/TIA-603-E-2016 - Section 2.2.12

#### **Test Settings**

- 1. RBW = 100kHz for emissions below 1GHz and 1MHz for emissions above 1GHz
- 2. VBW  $\geq$  3 x RBW
- 3. Span = 1.5 times the OBW
- 4. No. of sweep points ≥ 2 x span / RBW
- Detector = RMS
- Trace mode = Average (Max Hold for pulsed emissions)
- 7. The trace was allowed to stabilize

FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### **Test Setup**

The EUT and measurement equipment were set up as shown in the diagram below.

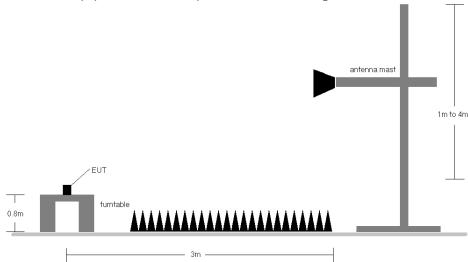


Figure 7-7. Test Instrument & Measurement Setup

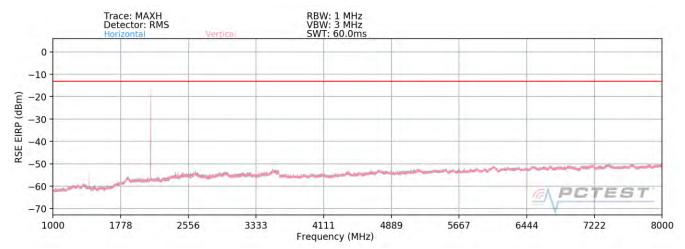
### **Test Notes**

- 1) Field strengths are calculated using the Measurement quantity conversions in KDB 971168 Section 5.8.4.
  - a) E(dBµV/m) = Measured amplitude level (dBm) + 107 + Cable Loss (dB) + Antenna Factor (dB/m)
  - b) EIRP (dBm) =  $E(dB\mu V/m) + 20logD 104.8$ ; where D is the measurement distance in meters.
- 2) The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The worst case emissions are reported with the EUT positioning, modulations, RB sizes and offsets, and channel bandwidth configurations shown in the tables below.
- 3) This unit was tested with its standard battery.
- The spectrum is measured from 9kHz to the 10th harmonic of the fundamental frequency of the transmitter. The worst-case emissions are reported.
- 5) Emissions below 18GHz were measured at a 3 meter test distance while emissions above 18GHz were measured at a 1 meter test distance with the application of a distance correction factor.
- 6) The "-" shown in the following RSE tables are used to denote a noise floor measurement.

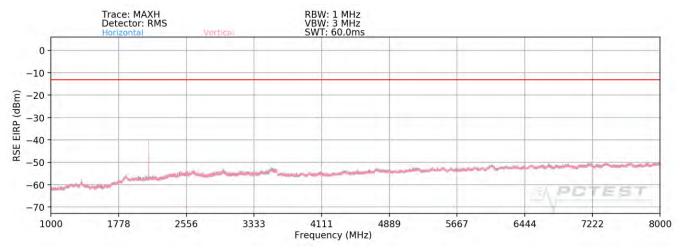
FCC ID: A3LSMF711JPN	Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### LTE Band 12



Plot 7-98. Radiated Spurious Plot (LTE Band 12 -Closed)



Plot 7-99. Radiated Spurious Plot (LTE Band 12 -Half-Open)

Bandwidth (MHz):	10
Frequency (MHz):	704.0
RB / Offset:	1 / 25

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
1408.0	V	168	258	-65.82	-2.25	38.93	-56.32	-13.00	-43.32
2112.0	V	149	209	-30.51	0.93	77.42	-17.84	-13.00	-4.84
2816.0	V	-	-	-77.46	1.97	31.51	-63.75	-13.00	-50.75
3520.0	V	-	-	-77.93	3.43	32.50	-62.76	-13.00	-49.76
4224.0	V	-	-	-78.00	3.23	32.23	-63.03	-13.00	-50.03

Table 7-5. Radiated Spurious Data (LTE Band 12 - Low Channel -Closed)

FCC ID: A3LSMF711JPN	Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Bandwidth (MHz):	10
Frequency (MHz):	707.5
RB / Offset:	1 / 25

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
1415.0	V	123	258	-64.32	-2.27	40.41	-54.85	-13.00	-41.85
2122.5	V	120	212	-30.16	0.95	77.79	-17.47	-13.00	-4.47
2830.0	V	-	-	-77.46	1.98	31.52	-63.74	-13.00	-50.74
3537.5	V	-	-	-78.22	3.70	32.48	-62.78	-13.00	-49.78
4245.0	V	-	-	-78.25	3.70	32.45	-62.80	-13.00	-49.80

Table 7-6. Radiated Spurious Data (LTE Band 12 – Mid Channel –Closed)

Bandwidth (MHz):	10
Frequency (MHz):	711.0
RB / Offset:	1 / 25

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
1422.0	V	116	252	-64.85	-2.40	39.75	-55.51	-13.00	-42.51
2133.0	V	209	195	-31.17	1.01	76.84	-18.42	-13.00	-5.42
2844.0	V	-	-	-77.55	2.04	31.49	-63.76	-13.00	-50.76
3555.0	V	-	-	-78.02	3.30	32.28	-62.97	-13.00	-49.97
4266.0	V	-	-	-78.68	3.81	32.13	-63.13	-13.00	-50.13

Table 7-7. Radiated Spurious Data (LTE Band 12 – High Channel –Closed)

Bandwidth (MHz):	10
Frequency (MHz):	707.5
RB / Offset:	1 / 25

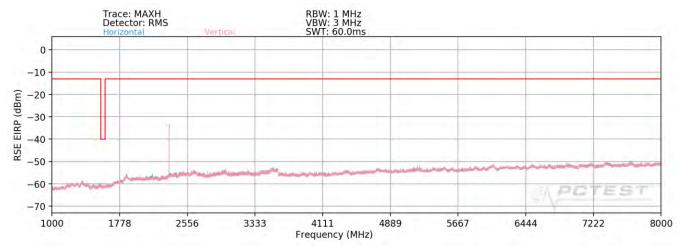
Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
1415.0	V	153	203	-71.04	-1.38	34.58	-60.68	-13.00	-47.68
2122.5	V	199	264	-34.78	2.16	74.38	-20.88	-13.00	-7.88
2830.0	V	-	-	-77.97	4.10	33.13	-62.12	-13.00	-49.12
3537.5	V	1	-	-78.00	4.74	33.74	-61.52	-13.00	-48.52
4245.0	V	-	-	-78.65	5.43	33.78	-61.48	-13.00	-48.48

Table 7-8. Radiated Spurious Data (LTE Band 12 – Mid Channel – WCP - Closed)

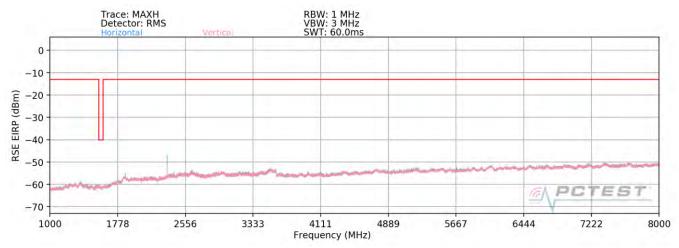
FCC ID: A3LSMF711JPN	PCTEST* Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### LTE Band 13



Plot 7-100. Radiated Spurious Plot (LTE Band 13 - Closed)



Plot 7-101. Radiated Spurious Plot (LTE Band 13 - Open)

	1
Bandwidth (MHz)	: 10
Frequency (MHz):	782.0
RB / Offset	1 / 25

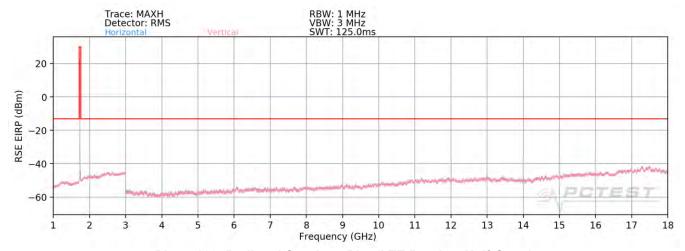
Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
1564.0	Н	-	-	-78.30	-2.52	26.18	-69.08	-40.00	-29.08
2346.0	Н	142	197	-51.41	1.72	57.31	-37.95	-13.00	-24.95
3128.0	Н	-	-	-79.23	2.42	30.19	-65.06	-13.00	-52.06
3910.0	Н		-	-80.31	3.48	30.17	-65.09	-13.00	-52.09
4692.0	Н	-	_	-79.68	4.65	31.97	-63.29	-13.00	-50.29

Table 7-9. Radiated Spurious Data (LTE Band 13 – Mid Channel – Closed)

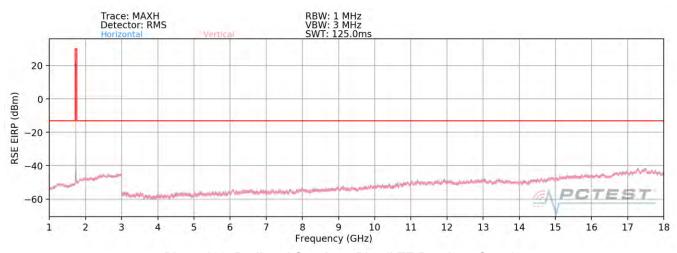
FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### LTE Band 4



Plot 7-102. Radiated Spurious Plot (LTE Band 4 -Half-Open)



Plot 7-103. Radiated Spurious Plot (LTE Band 4 – Open)

Bandwidth (MHz):	20
Frequency (MHz):	1720.0
RB / Offset:	1 / 50

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
3440.0	Н	-	-	-77.74	3.62	32.88	-62.38	-13.00	-49.38
5160.0	Н	364	92	-78.48	6.20	34.72	-60.54	-13.00	-47.54
6880.0	Н	-	-	-80.71	8.30	34.59	-60.66	-13.00	-47.66
8600.0	Н	-	-	-81.16	8.91	34.75	-60.51	-13.00	-47.51
10320.0	Н	-	_	-80.99	11.41	37.42	-57.84	-13.00	-44.84

Table 7-10. Radiated Spurious Data (LTE Band 4 – Low Channel –Half-Open)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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Bandwidth (MHz):	20
Frequency (MHz):	1732.5
RB / Offset:	1 / 50

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
3465.0	Н	126	217	-76.99	3.48	33.49	-61.77	-13.00	-48.77
5197.5	Н	-	-	-79.62	6.30	33.68	-61.58	-13.00	-48.58
6930.0	Н	-	-	-80.13	7.57	34.44	-60.81	-13.00	-47.81
8662.5	Н	-	-	-81.31	9.48	35.17	-60.09	-13.00	-47.09

Table 7-11. Radiated Spurious Data (LTE Band 4 - Mid Channel -Half-Open)

Bandwidth (MHz):	20
Frequency (MHz):	1745.0
RB / Offset:	1 / 50

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [cm]	Turntable Azimuth [degree]	Analyzer Level [dBm]	AFCL [dB/m]	Field Strength [dBµV/m]	EIRP Spurious Emission Level [dBm]	Limit [dBm]	Margin [dB]
3490.00	Н	-	-	-77.53	2.65	32.12	-63.13	-13.00	-50.13
5235.00	Н	299	370	-78.21	5.63	34.42	-60.84	-13.00	-47.84
6980.00	Н	-	-	-79.80	7.58	34.78	-60.48	-13.00	-47.48
8725.00	Н	-	-	-80.46	8.89	35.43	-59.83	-13.00	-46.83
10470.00	Н	-	-	-82.18	11.54	36.36	-58.90	-13.00	-45.90

Table 7-12. Radiated Spurious Data (LTE Band 4 – High Channel –Half-Open)

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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### 7.8 Frequency Stability / Temperature Variation

### **Test Overview and Limit**

Frequency stability testing is performed in accordance with the guidelines of ANSI/TIA-603-E-2016. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

For Part 27, the frequency stability shall be sufficient to ensure that the fundamental emission stays within the authorized frequency block.

### **Test Procedure Used**

ANSI/TIA-603-E-2016

#### **Test Settings**

- 1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
- 2. The equipment is turned on in a "standby" condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
- 3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

#### **Test Setup**

The EUT was connected via an RF cable to a spectrum analyzer with the EUT placed inside an environmental chamber.

#### **Test Notes**

None

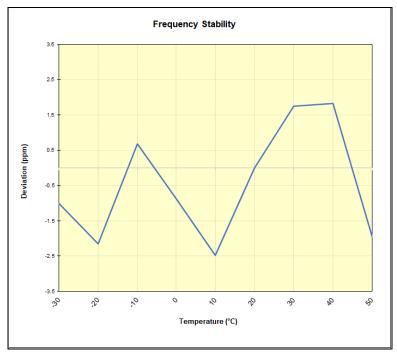
FCC ID: A3LSMF711JPN	Proud to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
Test Report S/N:	Test Dates:	EUT Type:		Page 76 of 80
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# Frequency Stability / Temperature Variation

LTE Band 12										
	Operating F	requency (Hz):	707,50	00,000						
	Ref.	Voltage (VDC):	4.	31						
		Deviation Limit:	± 0.00025%	or 2.5 ppm						
Voltage (%)	Power (VDC)	Temp (°C)	Frequency (Hz)	Freq. Dev. (Hz)	Deviation (%)					
		- 30	702,985,608	-703	-0.0001000					
		- 20	702,984,794	-1,518	-0.0002159					
		- 10	702,986,787	476	0.0000677					
		0	702,985,697	-614	-0.0000874					
100 %	4.31	+ 10	702,984,570	-1,741	-0.0002477					
		+ 20 (Ref)	702,986,311	0	0.0000000					
		+ 30	702,987,546	1,235	0.0001756					
		+ 40	702,987,601	1,289	0.0001834					
		+ 50	702,984,940	-1,371	-0.0001950					
Battery Endpoint	3.60	+ 20	702,986,506	195	0.0000277					

Table 7-13. LTE Band 12 Frequency Stability Data



Plot 7-104. LTE Band 12 Frequency Stability Chart

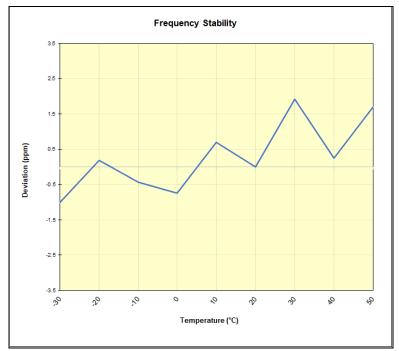
FCC ID: A3LSMF711JPN	Pout to be part of @element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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# **Frequency Stability / Temperature Variation**

LTE Band 13					
	Operating F	Operating Frequency (Hz):		782,000,000	
	Ref.	Voltage (VDC):	4.31		
		Deviation Limit:	± 0.00025% or 2.5 ppm		
Voltage (%)	Power (VDC)	Temp (°C)	Frequency (Hz)	Freq. Dev. (Hz)	Deviation (%)
		- 30	777,492,658	-777	-0.0001000
		- 20	777,493,574	139	0.0000179
		- 10	777,493,100	-336	-0.0000432
		0	777,492,862	-573	-0.0000737
100 %	4.31	+ 10	777,493,975	540	0.0000694
		+ 20 (Ref)	777,493,436	0	0.0000000
		+ 30	777,494,933	1,498	0.0001927
		+ 40	777,493,629	193	0.0000248
		+ 50	777,494,758	1,322	0.0001701
Battery Endpoint	3.60	+ 20	777,493,691	255	0.0000329

Table 7-14. LTE Band 13 Frequency Stability Data



Plot 7-105. LTE Band 13 Frequency Stability Chart

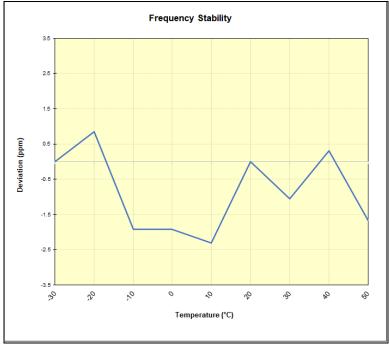
FCC ID: A3LSMF711JPN	Proud to be part of (8) element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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# **Frequency Stability / Temperature Variation**

LTE Band 4						
	Operating F	requency (Hz):	1,732,500,000			
	Ref.	Voltage (VDC):	4.31			
		Deviation Limit:	± 0.00025% or 2.5 ppm			
Voltage (%)	Power (VDC)	Temp (°C)	Frequency (Hz)	Freq. Dev. (Hz)	Deviation (%)	
	4.31	- 30	1,723,508,044	0	0.0000000	
		- 20	1,723,509,509	1,465	0.0000850	
		- 10	1,723,504,748	-3,296	-0.0001912	
100 %		0	1,723,504,741	-3,303	-0.0001916	
		+ 10	1,723,504,067	-3,977	-0.0002308	
		+ 20 (Ref)	1,723,508,044	0	0.0000000	
		+ 30	1,723,506,221	-1,823	-0.0001058	
		+ 40	1,723,508,579	535	0.0000311	
		+ 50	1,723,505,175	-2,869	-0.0001665	
Battery Endpoint	3.60	+ 20	1,723,508,252	208	0.0000121	

Table 7-15. LTE Band 4 Frequency Stability Data



Plot 7-106. LTE Band 4 Frequency Stability Chart

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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# 8.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSMF711JPN** complies with all the requirements of Part 27 of the FCC rules.

FCC ID: A3LSMF711JPN	Proud to be part of ® element	PART 27 MEASUREMENT REPORT	SAMSUNG	Approved by: Technical Manager
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